

Search Notes

Application/Control No.

10/760,505

Examiner

Lois Zheng

Applicant(s)/Patent under
Reexamination

HIRAIWA ET AL.

Art Unit

1742

SEARCHED

Class	Subclass	Date	Examiner
204	242	2/9/2007	LLZ
204	243.1	2/9/2007	LLZ
204	274	2/9/2007	LLZ
205	355-356	2/9/2007	LLZ

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
inventorship search	2/9/2007	LLZ
Updated EAST search	2/9/2007	LLZ